

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/620,862	ANVIN ET AL.	
Examiner	Art Unit	
BENJAMIN P. GEIB	2181	

SEARCHED					
Class	Subclass	Date	Examiner		

INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		